

Main Unit Spec

Model Type	KrF (248 nm) DUV Stepper
Wafer Size	200 mm; 150 mm; 125 mm; 100 mm
Resolution	≤ 150 nm
Reticle Size	6 in. (0.25 in. thick)
Reduction Ratio	5:1
Field Size	22 mm x 22 mm
Overlay Accuracy	≤ 25 nm ($ m + 3\sigma$)
Options	Special Substrate Handling Pellicle Particle Checker PC Remote Console Online Functions